Contents:

H-field probe	RF-R 3 - 2
H-field probe	RF-U 2,5 - 2
H-field probe	RF-K 7 - 4
E-field probe	RF-E 10

Cable SMB-BNC
Case 175x140x32 mm
Instructions

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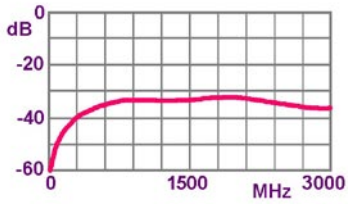
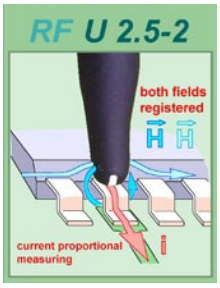
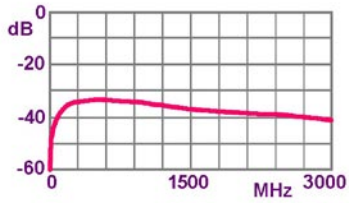
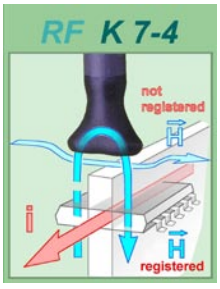
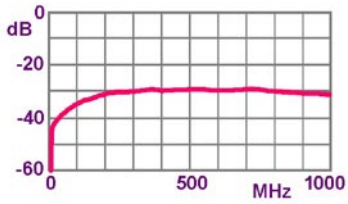
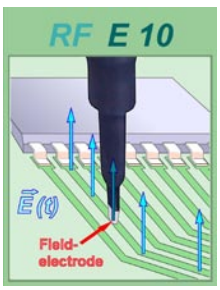
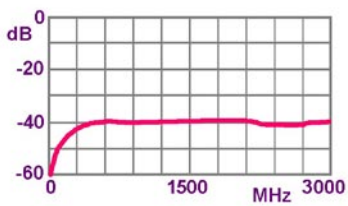
Instructions

The RF 1 probe set contain magnetic/electric field probes for examining PCB's during development. Magnetic and electric fields measurements on conductors, components and modules of the supply system are the basis for concerted measures to reduce radiated emissions.
The passive probes are connected to the 50 Ohm input of a spectrum analyser or oscilloscope and facilitate comparison measurements of magnetic/electric fields and disturbance currents in the frequency range from 30 MHz up to 3 GHz.
All probes have a sheath current damping and are electrically screened.

NEAR FIELD PROBE SET RF 1

FREQUENCY RANGE 30 MHz up to 3 GHz

Application	Description	Characteristic
	**RF-R 3 - 2** The near field probe is designed for the detection of HF magnetic fields with a high geometrical resolution. The field orientation and distribution can be detected by moving the probe around conductor runs, bypass capacitors, EMC components and within IC pin and supply system areas. **Frequency range: 30 MHz to 3 GHz** **Resolution approx. 1 mm**	
	**RF-U 2,5 - 2** The near field probe is designed for the selective detection of RF currents in conductor runs, component connections, capacitors and IC pins. The probe head has a magnetically active curb with a width of approx. 0.5 mm. The probe's curb is positioned on conductor runs, ICs or capacitor connections for a measurement. **Frequency range: 30 MHz to 3 GHz** **Resolution approx. 0.5 mm**	
	**RF-K 7 - 4** The near field probe detects contra-orientated magnetic fields within the two halves of the probe's head; these can be the circular magnetic fields of larger objects such as IC substrates and wide conducting paths. The effect of homogeneous fields is sufficiently compensated for by the probe's special head. The probe is especially suitable for detecting the non-homogeneous fringe magnetic field of flat units. **Frequency range: 30 MHz to 1 GHz** **Resolution approx. 5 mm**	
	**RF-E 10** The near field probe detects electrical fields which are emitted from the surface of clocked leads. The probe head's tip is only 0.5 mm wide. Its integrated shielding prevents neighbouring leads from interfering with the measurement result. A resolution of approx. 0.2 mm is possible so that each individual conductor run can be evaluated in the layout. **Frequency range: 30 MHz to 3 GHz** **Resolution approx. 0.2 mm**	

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